Simultaneous phase matching and internal interference of two second-order nonlinear parametric processes: erratum

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Abstract: An erratum is presented to correct the figure caption of Fig. 4.

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References and links

1. B. F. Johnston, P. Dekker, M. J. Withford, S. M. Saltiel, and Y. S. Kivshar, " Simultaneous phase matching and internal interference of two second-order nonlinear parametric processes," Opt. Express 14, 11756-11765 (2006).

In the subject paper [1] a mistake in the figure caption of Fig. 4 was noticed. The colors for the data representing the two interactions Type I and Type II were interchanged. The correct figure caption follows:

Fig. 4. Experimental (dots) and theoretical (lines) temperature phase-matching curves for SHG Type I (red) and SHG Type 0 (blue) in the 45.75 µm and 45.79 µm period gratings. (a) 45.79 µm grating with ~ 6 nm deviation from the ideal calculated grating for DPM of the two processes. (b) 45.75 µm grating with ~50 nm deviation from the ideal calculated grating for DPM of the two processes.